

# FXLP4555 1.8V / 3.0V SIM Card Power Supply and Level Shifter

### Features

- Supports 1.8V or 3.0V SIM Cards
- LDO Supplies >50mA Under 1.8V and 3.0V
- Built-in Pull-up Resistor for I/O Pin in Both Directions
- ESD Protection: 8kV (Human Body Model, According to ISO-7816 Specifications)
- Supports Clock ≥ 5MHz
- Supports "Clock Stop" Power Management per ISO7816-3 Specifications
- Low-Profile 3x3mm MLP-16 Package

### **Applications**

- SIM Card Interface Circuit for 2G, 2.5G, and 3G Mobile Phones
- Identification Module
- Smart Card Readers
- Wireless PC Cards

# Description

The FXLP4555 is a level-shifter analog circuit designed to translate the voltages between a SIM card and an external baseband. A built-in LDO-type DC-DC converter allows the FXLP4555 to drive 1.8V and 3.0V SIM cards. The device fulfills the ISO7816-3 smart-card interface standard as well as GSM 11.11 (11.12 and 11.18) and 3G mobile requirements (IMT-2000/3G UICC standard). The EN pin enables a low-current Shutdown Mode that extends battery life. The card power supply voltage (VCC\_C) is selected using a single pin (VSEL).

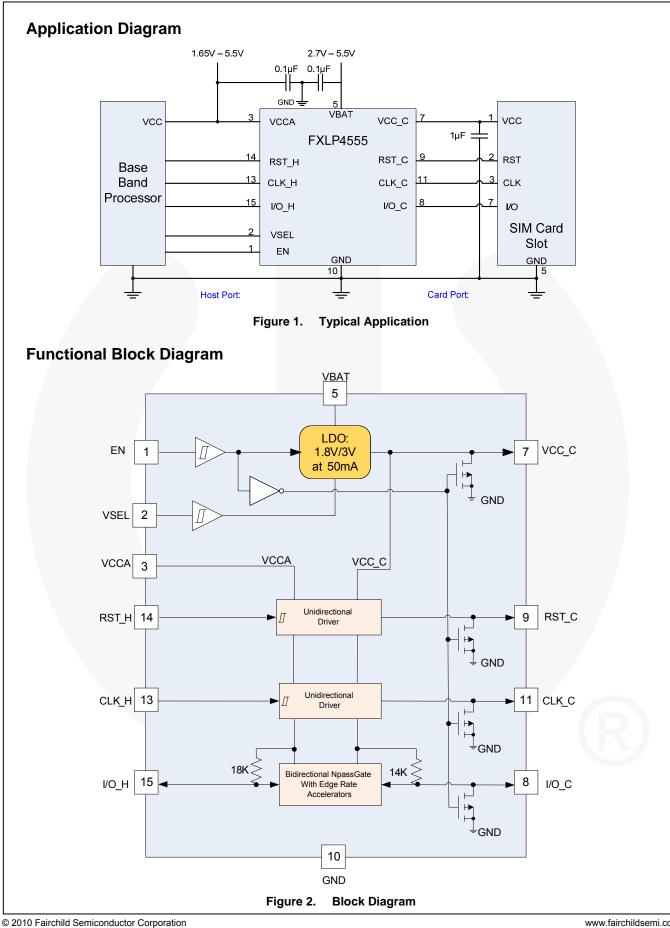


#### **Ordering Information**

Part Number	Part Number Operating Temperature Range		Package	Packing Method	
FXLP4555MPX	-40 to +85°C	FXLP 4555	16-Lead,MLP,Quad,JEDEC MO-220,3MM Square	3000 Units on Tape & Reel	

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# **Pin Configuration**

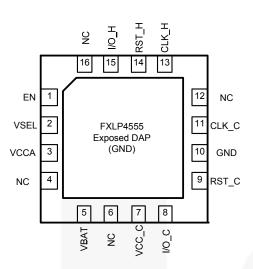


Figure 3. Pin Assignments (Top View)

# **Pin Definitions**

Pin	Name	Туре	Description
1	EN	INPUT	Power-Down Mode. EN=LOW $\rightarrow$ low-current Shutdown Mode activated. EN=HIGH $\rightarrow$ normal operation. A LOW level on this pin resets the SIM interface, switching off the V <sub>CC_C</sub> .
2	VSEL	INPUT	The signal present on this pin programs the SIM_V <sub>CC</sub> value: VSEL=LOW $\rightarrow$ SIM_V <sub>CC</sub> =1.8V; VSEL=HIGH $\rightarrow$ SIM_V <sub>CC</sub> =3V.
3	VCCA	POWER	Connected to the baseband power supply; this pin configures the level shifter input stage to accept signals from the baseband. A 0.1 $\mu$ F capacitor is used to bypass the power supply voltage. When V <sub>CCA</sub> is below 1.1V (typical), the V <sub>CC_C</sub> (SIM Card V <sub>CC</sub> ) is disabled and FXLP4555 enters Shutdown Mode.
4	NC		No connect. It is recommended to solder to PCB GND.
5	VBAT	POWER	LDO converter supply input. The input voltage ranges from 2.7V to 5.5V. This pin needs to be bypassed by a $0.1\mu$ F capacitor.
6	NC		No connect. It is recommended to solder to PCB GND.
7	vcc_c	POWER	Connected to the SIM card power supply pin. An internal LDO converter is programmable by the external baseband to supply either 1.8V or 3.0V output voltage. An external 1.0 $\mu$ F minimum ceramic capacitor must be connected across V <sub>CC_C</sub> and GND. During a normal operation, the V <sub>CC_C</sub> voltage can be set to 1.8V, followed by a 3.0V value, or can start directly at either of these values.
8	I/O_C	INPUT/ OUTPUT	Handles the connection to the serial I/O of the card connector. A bi-directional level translator adapts the serial I/O signal between the card and the baseband. A $14k\Omega$ (typical) pull-up resistor provides a high-impedance state for the SIM card I/O link.
9	RST_C	OUTPUT	Connected to the RESET pin of the card connector. A level translator adapts the external reset (RST) signal to the SIM card.
10	GND	GROUND	Ground reference for the integrated circuit and associated signals. Care must be taken to avoid voltage spikes when the device operates in normal operation.
11	CLK_C	OUTPUT	Connected to the CLOCK pin of the card connector. The CLOCK (CLK) signal comes from the external clock generator; the internal level shifter adapts the voltage defined for the $V_{CC_c}$ .
12	NC		No connect. It is recommended to solder to PCB GND.
13	CLK_H	INPUT	The clock signal, coming from the external controller, must have a duty cycle within the range defined by the specification (typically 50%). The built-in level shifter translates the input signal to the external SIM card CLK input.

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# Pin Definitions (Continued)

Pin	Name	Туре	Description
14	RST_H	INPUT	The RESET signal present at this pin is connected to the SIM card through the internal level shifter, which translates the level according to the $V_{CC_C}$ programmed value.
15	I/O_H	INPUT/ OUTPUT	This pin is connected to the baseband. A bidirectional level translator adapts the serial I/O signal between the smart card and the baseband. A built-in constant $18k\Omega$ (typical) resistor provides a high-impedance state when not activated.
16	NC		No connect. It is recommended to solder to pcb GND.
17	Exposed DAP	Ground	Must be soldered to PCB ground plane.

# **Absolute Maximum Ratings**

Stresses exceeding the absolute maximum ratings may damage the device. The device may not function or be operable above the recommended operating conditions and stressing the parts to these levels is not recommended. In addition, extended exposure to stresses above the recommended operating conditions may affect device reliability. The absolute maximum ratings are stress ratings only.  $T_A$ =+25°C.

Symbol	Parameter			Min.	Тур.	Max.	Unit	
$V_{BAT}$	LDO Power Supply Voltage			-0.5	V <sub>BAT</sub>	6.0	V	
V <sub>CCA</sub>	Power Supply from Baseband Side			-0.5	V <sub>CCA</sub>	6.0	V	
V <sub>cc_c</sub>	External Card	Power Supply		-0.5	V <sub>cc_c</sub>	6.0	V	
V <sub>IN</sub>	Digital Input Pin Voltage			-0.5	V <sub>IN</sub>	V <sub>CCA</sub> +0.5, but <6.0	V	
I <sub>IN</sub>	Digital Input F	Pin Current		-5		+5	mA	
V <sub>OUT</sub>	Digital Output	Pin Voltage		-0.5	Vout	V <sub>CCA</sub> +0.5, but <6.0	V	
I <sub>OUT</sub>	Digital Output	Digital Output Pin Current				+10	mA	
V <sub>OUT_SIM</sub>	SIM Card Output Pin Voltage			-0.5	V <sub>OUT</sub>	SIM_V <sub>CC</sub> + 0.5<6.0	V	
I <sub>OUT_SIM</sub>	SIM Card Output Pin Current <sup>(1)</sup>					15	mA	
PD	Power Dissipation at T <sub>A</sub> =+85°C					440	mW	
$\Theta_{JA}$	Thermal Resistance, Junction-to-Air					72	°C/W	
T <sub>A</sub>	Operating Ambient Temperature Range			-40		+85	°C	
TJ	Operating Junction Temperature Range			-40		+125	°C	
T <sub>JMAX</sub>	Maximum Jun	ction Temperatu	re			+125	°C	
T <sub>STG</sub>	Storage Temp	perature Range		-65		+150	°C	
	SD Electrostatic Discharge Capability Human Body Model, JESD22-A114 R=1500Ω, C=100pF	Hun	Human Body	SIM Card Pins (7,8,9,10,11)		8000		
ESD Discha		All Other Pins		2000		V		
	Charged Device Model,		SIM Card Pins (7,8,9,10,11)	2000				
	JESD22-C101 All Other Pins			600			-	
	Moisture Sens	sitivity Level			1		Level	

Notes:

1. Internally limited.

2. Meets or exceeds JEDEC specification EIA/JESD78 IC latchup test.

# **Electrical Characteristics**

 $T_A$ =-40°C to +85°C. Device meets the specifications after thermal equilibrium has been established when mounted in a test socket or printed circuit board with maintained transverse airflow greater than 500lfpm. Electrical parameters are guaranteed only over the declared operating temperature range. Functional operation of the device exceeding these conditions is not implied. Device specification limit values are applied individually under normal operating conditions and not valid simultaneously.

Symbol	Parameter	Condition	Min.	Тур.	Max.	Unit
Power Supp	ly Section					
V <sub>BAT</sub>	Power Supply		2.7		5.5	V
I V <sub>BAT</sub>	Operating Current	$I_{CC}$ =0mA, $V_{BAT}$ > 3.0V if $V_{SEL}$ =1 or $V_{BAT}$ > 2.7V if $V_{SEL}$ =0		16	25	μA
$IV_{BAT_{SD}}$	Shutdown Current	EN=Low			3	μA
V <sub>CCA</sub>	Operating Voltage		1.65		5.50	V
IVCCA	Operating Current <sup>(3)</sup>	fCLK=1MHz		7	12	μA
IV <sub>CCA_SD</sub>	Shutdown Current	EN=Low			1	μA
V <sub>CCA</sub>	Under-Voltage Lockout		0.6		1.5	V
		$V_{SEL}$ =High, $V_{BAT}$ =3.0V, $IV_{CC_C}$ =50mA		2.8		
V <sub>cc_c</sub>	SIM Card Supply Voltage	$V_{SEL}$ =High, $V_{BAT}$ =3.3V – 5.5V, $IV_{CC_C}$ =0mA - 50mA	2.8	3.0	3.2	V
		VSEL=Low, $V_{BAT}$ =2.7V – 5.5V, $IV_{CC_C}$ =0mA - 50mA	1.7	1.8	1.9	
lvcc_c_sc	Short-Circuit Current	$V_{CC_C}$ Shorted to Ground, T <sub>A</sub> =25°C			175	mA
Digital Input	/ Output Section (CLK,	RST, I/O, EN, VSEL <b>)</b>				
VIN	Input Voltage Range	EN, VSEL, RST_H, CLK_H, I/O_H	0		V <sub>CCA</sub>	V
I <sub>IH</sub> , I <sub>IL</sub>	Input Current	EN, VSEL, RST_H, CLK_H	-100		100	nA
VIH	High Level Input Voltage	RST_H, CLK_H, EN, VSEL	0.7 • V <sub>CCA</sub>		V <sub>CCA</sub>	V
VIL	Low Level Input	RST_H, CLK_H			0.2 * V <sub>CCA</sub>	v
	Voltage	EN, VSEL	0		0.4	-
V <sub>OH_I/O</sub>	High Level Output Voltage	I/O_C=V <sub>CC_C</sub> , I <sub>OH_I/O</sub> =-20µА	0.7 • V <sub>CCA</sub>		V <sub>CCA</sub>	V
V <sub>OL_I/O</sub>	Low Level Output Voltage	I/O_C=0 V, Ι <sub>ΟL_//Ο</sub> =200μΑ	0		0.4	V
I <sub>IH</sub>	High Level Input Current	I/O	-20		20	μA
IIL	Low Level Input Current	I/O			1.0	mA
R <sub>pu_I/O_H</sub>	I/O Pull-Up Resistor		12	18	24	kΩ

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Symbol	Parameter	Condition	Min.	Тур.	Max.	Unit
SIM Interfac	e Section <sup>(4)</sup>	- <b>I</b>			1	
		Output RST_C V <sub>OH</sub> at I <sub>RST_C</sub> =-20µA	0.9 • Vcc_c		V <sub>cc_c</sub>	V
	V <sub>CC C</sub> =+3.0V	Output RST_C VoL at IRST_C=+200µA	0		0.4	V
	(V <sub>SEL</sub> =HIGH)	Output RST_C Rise Time at $C_{OUT}$ =30pF (10% - 90%) <sup>(3)</sup>			1	μs
DOT O		Output RST_C Fall Time at $C_{OUT}$ =30pF (90% - 10%) <sup>(3)</sup>			1	μs
RST_C		Output RST_C V <sub>OH</sub> at I <sub>RST_C</sub> =-20µA	0.9 • V <sub>CC_C</sub>		V <sub>cc_c</sub>	V
	V = 1 0V	Output RST_C VoL at IRST_C=+200µA	0		0.4	V
	V <sub>CC_C</sub> =+1.8V (V <sub>SEL</sub> =LOW)	Output RST_C Rise Time at $C_{OUT}$ =30pF (10% - 90%) <sup>(3)</sup>			1	μs
		Output RST_C Fall Time at $C_{OUT}$ =30pF (90% - 10%) <sup>(3)</sup>			1	μs
	V <sub>CC_C</sub> =+3.0V (V <sub>SEL</sub> =HIGH)	Output Duty Cycle	40		60	%
		Maximum Output Frequency	5			MHz
		Output V <sub>OH</sub> at I <sub>CLK_C</sub> =-20µA	0.9 • V <sub>CC_C</sub>		V <sub>cc_c</sub>	V
		Output V <sub>OL</sub> at $I_{CLK_C}$ =+200µA	0		0.4	V
		Output CLK_C Rise Time at $C_{OUT}$ =30pF (10% - 90%) <sup>(3)</sup>			18	ns
CLK C		Output CLK_C Fall Time at $C_{OUT}$ =30pF (90% - 10%) <sup>(3)</sup>			18	ns
ULK_U		Output Duty Cycle	40		60	%
		Maximum Output Frequency	5			MHz
	V <sub>CC_C</sub> =+1.8V (V <sub>SEL</sub> =LOW)	Output V <sub>OH</sub> at I <sub>CLK_C</sub> =-20µA	0.9 • V <sub>CC_C</sub>		V <sub>cc_c</sub>	V
		Output V <sub>OL</sub> at I <sub>CLK_C</sub> =+200µA	0		0.4	V
		Output CLK _C Rise Time at $C_{OUT}$ =30pF (10% - 90%) <sup>(3)</sup>			18	Ns
		Output CLK_C Fall Time at C <sub>OUT</sub> =30pF (90% - 10%) <sup>(3)</sup>			18	ns

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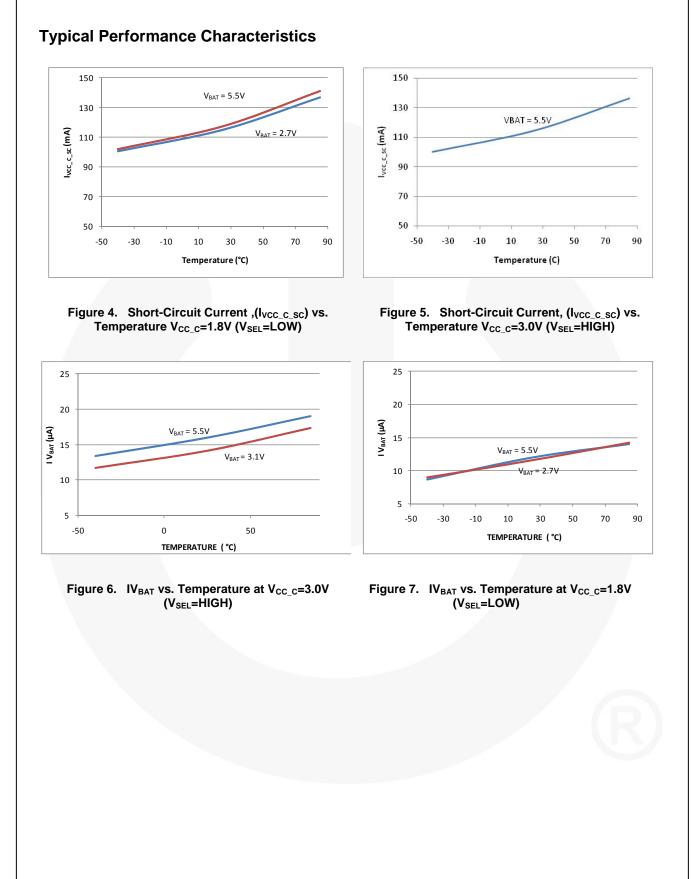
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Symbol	Parameter	Condition	Min.	Тур.	Max.	Unit
		Output V <sub>OH</sub> at $I_{I/O_C}$ =-20µA, V <sub>I/O</sub> =V <sub>DD</sub>	0.8 • V <sub>CC_C</sub>		V <sub>cc_c</sub>	V
		Output V <sub>OL</sub> at $I_{I/O_C}$ =+1mA, V <sub>I/O</sub> =0V	0		0.4	V
	V <sub>CC_C</sub> =+3.0V (V <sub>SEL</sub> =HIGH)	I/O_C Rise Time at C <sub>OUT</sub> =30pF (10% - 90%) <sup>(3)</sup>			1	μs
1/0 0		I/O_C Fall Time at C <sub>OUT</sub> =30pF (90% - 10%) <sup>(3)</sup>			1	μs
I/O_C	V <sub>CC_C</sub> =+1.8V (V <sub>SEL</sub> =LOW)	Output $V_{OH}$ at $I_{I/O_C}$ =-20µA, $V_{I/O}$ = $V_{DD}$	0.8 • V <sub>CC_C</sub>		V <sub>cc_c</sub>	V
		Output V <sub>OL</sub> at I <sub>I/O_C</sub> =+1mA, V <sub>I/O</sub> =0V	0		0.3	V
		I/O_C Rise Time at C <sub>OUT</sub> =30Pf (10% - 90%) <sup>(3)</sup>			1	μs
		I/O_C Fall Time at C <sub>OUT</sub> =30pF (90% - 10%) <sup>(3)</sup>			1	μs
R <sub>pu_l/O_C</sub>	Card I/O Pull-Up Resistor		10	14	18	kΩ

Notes:

3. Guaranteed by design over the specified operating temperature range.

4. All the dynamic specifications (AC specifications) are guaranteed by characterization over the specified operating temperature range, unless otherwise indicated.



# **Application Information**

#### Card Supply Converter

The FXLP4555 interface DC-DC converter is a Low Dropout (LDO) voltage regulator capable of supplying a current in excess of 50mA under 1.8V or 3.0V. Quiescent current is typically lower than  $20\mu A$  (see Figure 6 and Figure 7). VSEL is a select input, allowing a logic level signal to select a regulated voltage of 1.8V (VSEL = LOW) or 3.0V (VSEL = HIGH).

FXLP4555 has a shutdown input (EN) that allows it to turn off or turn on the regulator output. Figure 8 shows a simplified view of the voltage regulator. The V<sub>CC\_C</sub> output is internally current limited and protected against short circuits. The short-circuit current ( $I_{VCC_CC_SC}$ ) is constant over the SIM Card V<sub>CC</sub> and V<sub>BAT</sub>, while it varies with operating temperature, typically in the range of 90mA to 140mA (Figure 4 and Figure 5).

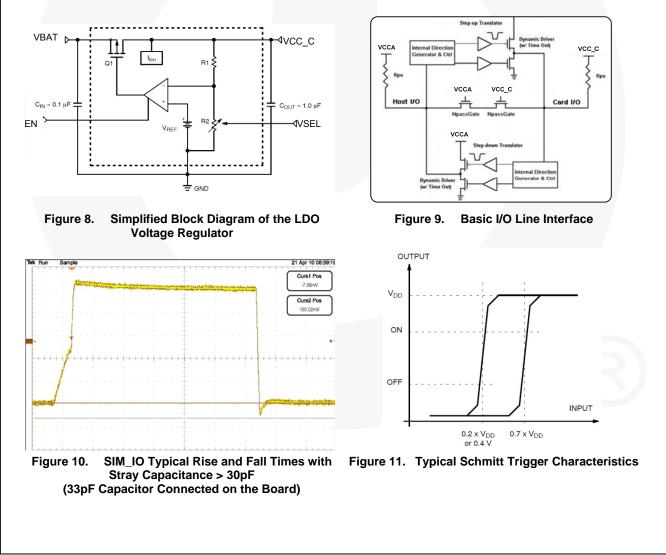
To guarantee a stable LDO, the VCC\_C output is connected to a  $1.0\mu F$  bypass ceramic capacitor to ground. At the input, V<sub>BAT</sub> is bypassed to ground with a  $0.1\mu F$  ceramic capacitor.

# Level Shifters

The level shifters accommodate any voltage difference between the Baseband (BB) Processor (1.65V - 5.5V) and the SIM card (1.8V or 3V). The RESET and CLOCK level shifters are uni-directional (from BB to SIM).

The bidirectional I/O line automatically adapts the voltage difference between the baseband and the SIM card in both directions. In addition, with the pull-up resistor, an active edge rate accelerator circuit (*see Figure 9*) provides a fast charge of the stray capacitance, yielding a rise time within the ISO7816-3 specifications.

The typical waveform provided in Figure 10 shows how the accelerator operates. Two distinct slew rates are observed. From 0V to approximately VCC/2, the slew rate is the RC time constant of the pull-up resistor and the stray capacitance. When the input slope crosses the VCC/2 threshold, the edge rate accelerator is activated, resulting in the faster slew rate from approximately VCC/2 to V<sub>CC</sub> as depicted in Figure 10.



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# Applications Information (Continued)

#### Input Schmitt Triggers

All the logic input pins (except I/O H and I/O C) have built-in Schmitt trigger circuits to prevent uncontrolled operation. Typical dynamic characteristics of the related pins are depicted in Figure 11.

The output signal is guaranteed to go HIGH when the input voltage is above  $0.7 \text{ x V}_{DD}$  and go LOW when the input voltage is below 0.4V. See Electrical Characteristics section.

#### Shutdown Operating

To save power, it is possible to put the FXLP4555 in Shutdown Mode by setting the pin EN LOW. The device enters Shutdown Mode automatically when V<sub>CCA</sub> goes lower than 1.1V typically.

#### ESD Protection

The FXLP4555 SIM interface features an HBM ESD voltage protection in excess of 7kV for all the SIM pins (IO\_C, CLK\_C, RST\_C, VCC\_C and GND). All the other pins (Host side) sustain at least 2kV. The HBM ESD voltage required by the ISO7816 standard is 4kV.

#### Printed Circuit Board (PCB) Layout

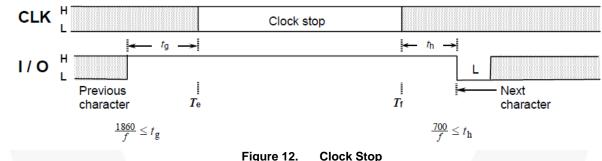
Careful layout routing should be applied to achieve efficient operating of the device in its mobile or portable environment and to fully exploit its performance.

The bypass capacitors must be connected as close as possible to the device pins (VCC\_C, VCCA, or VBAT) to reduce possible parasitic behaviors (ripple and noise). It is recommended to use ceramic capacitors.

The exposed pad should be connected to ground as well as the unconnected pins (NC). A relatively large ground plane is recommended.

#### Clock Stop

Section 6.3.2 of ISO7816-3 identifies the "Power Management" feature of Clock Stop. For cards supporting Clock Stop, when the interface device expects no transmission from the card and when I/O has remained at state H for at least 1,860 clock cycles (delay  $t_{a}$ ), then according to Figure 13, the interface device may stop the clock on CLK (at time te) while the SIM card V<sub>CC</sub> remains powered and RST at state H.

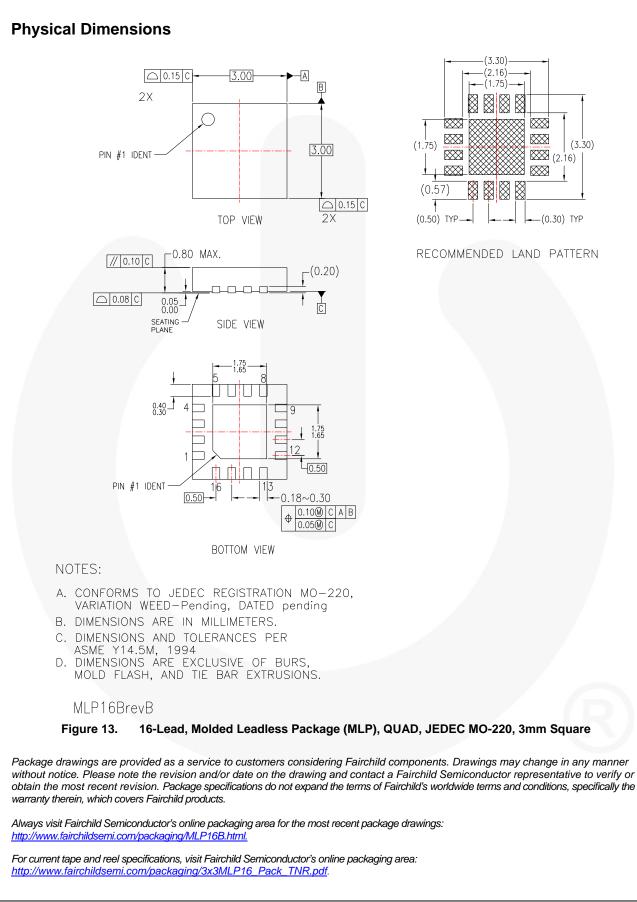


When the clock is stopped (from time te to time tf), CLK shall be maintained either at state H or at state L, according to the clock stop indicator X defined in section 8.3 of the ISO7816-3 specification.

At time t<sub>f</sub>, the interface device restarts the clock and the information exchange on I/O may continue after at least 700 clock cycles (at time  $t_f + t_h$ ).

#### Clock Stop

The FXLP4555 supports the above description of Clock Stop per ISO7816-3 specifications.



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Obsolete

Not In Production

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